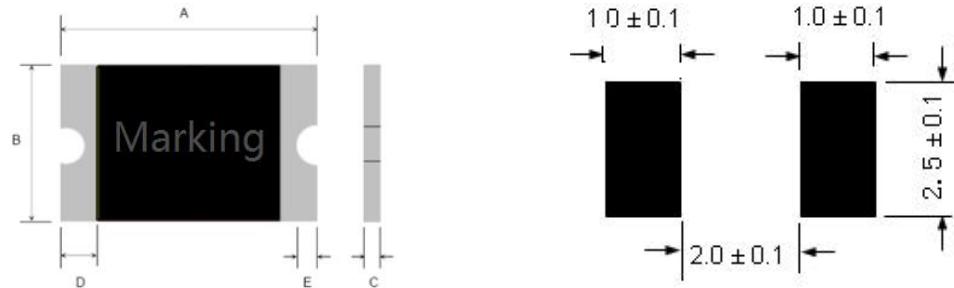


## SMD1210-035-16V

### Shape and Size



Terminal pad materials :Tin-Plated Nickle-copper

Terminal pad solderability : Meets EIA specification RS 186-9E and ANSI/J-STD-002 Category 3.

### Dimention(Unit : mm)

Model	A		B		C		D
	Min.	Max.	Min.	Max.	Min.	Max	Min.
SMD1210-035-16v	3.00	3.43	2.35	2.80	0.35	0.85	0.25

### Performance Ratings:

Model	V <sub>max</sub> (V <sub>dc</sub> )	I <sub>max</sub> (A)	I <sub>hold</sub> @25°C (A)	I <sub>trip</sub> @25°C (A)	P <sub>d</sub> Typ (W)	Maximum Time To Trip		Resistance		
						Current (A)	Time (Sec)	R <sub>i</sub> <sub>min</sub> (Ω)	R <sub>i</sub> <sub>typ</sub> (Ω)	R <sub>i</sub> <sub>max</sub> (Ω)
SMD1210-035	16	100	0.35	0.75	0.6	8.0	0.20	0.200	0.550	1.300

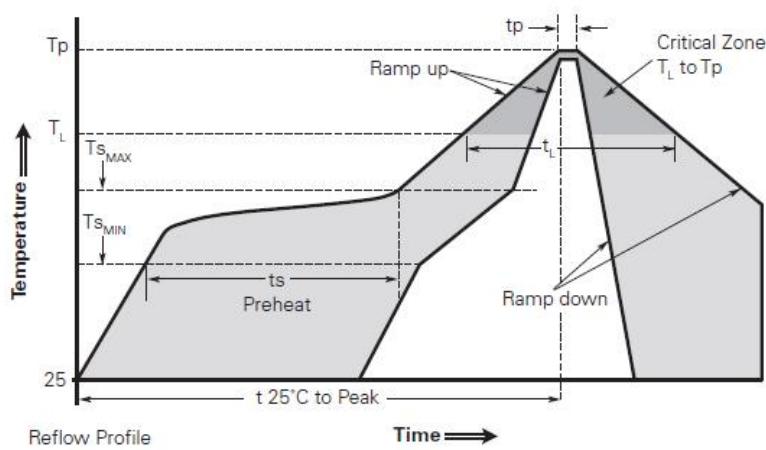
### Test Conditons and Standards:

I <sub>tem</sub>	Test Conditon	Standard
Initial Resistance	25°C	0.200~1.300Ω
I <sub>u</sub>	25°C, 0.35A, 60min	No Trip
T <sub>trip</sub>	25°C, 8.0A	<0.20s
Trip endurance	16V, 100A, 60min	No arcing or burning

Operating Temperature: -40°C TO 85°C

Packaging: Bulk 4000 pcs per bag

### Solder Reflow Conditions



<u>Profile Feature</u>	Pb-Free Assembly	
• Average ramp up rate(T <sub>S</sub> <sub>MAX</sub> to T <sub>P</sub> )		3°C/Second max
<u>Preheat</u>		
• Temperature min (T <sub>S</sub> <sub>MIN</sub> )	150°C	• Recommended reflow methods: IR, vapor phase oven, hot air oven, N2 environment for lead-free.
• Temperature max (T <sub>S</sub> <sub>MAX</sub> )	200°C	• Devices are not designed to be wave soldered to the bottom side of the board.
• Time(T <sub>S</sub> <sub>MIN</sub> to T <sub>S</sub> <sub>MAX</sub> )	60-120 Seconds	• Recommended maximum paste thickness is 0.25mm (0.010inch).
<u>Time maintained above:</u>		
• Temperature(T <sub>L</sub> )	217°C	• Devices can be cleaned using standard industry methods and solvents.
• Time(T <sub>L</sub> )	60-150 Seconds	• Soldering temperature profile meets RoHS leadfree process.
• Peak/Classification temperature(T <sub>P</sub> )	260°C	
<u>Time within 5°C of actual peak temperature</u>		
• Time(T <sub>P</sub> )	30 Seconds max	
• Ramp down rate	3°C/Second max	
• Time 25°C to peak temperature	8 minutes max	

Note: All temperatures refer topside of the package.measured on The package body surface

Notes: If reflow temperatures exceed the recommended profile, devices may not meet the performance requirements

## Storage

The maximum ambient temperature shall not exceed 38 °C . Storage temperatures higher than 38 °C could result in the deformation of packaging materials. The maximum relative humidity recommended for storage is 60%. High humidity with high temperature can accelerate the oxidation of the solder plating on the termination and reduce the solderability of the components. Sealed plastic bags with desiccant shall be used to reduce the oxidation of the termination and shall only be opened prior to use. The products shall not be stored in areas where harmful gases containing sulfur or chlorine are present

## Warning

Use PPTC beyond the maximum ratings or improper use may result in device damage and possible electrical arcing and flame.

PPTC are intended for protection against occasional over current or over temperature fault conditions and should not be used when repeated fault conditions or prolonged trip events are anticipated.

Device performance can be impacted negatively if devices are handled in a manner inconsistent with recommended electronic, thermal, and mechanical procedures for electronic components.

Use PPTC with a large inductance in circuit will generate a circuit voltage (L di/dt) above the rated voltage of the PPTC.

Avoid impact PPTC device its thermal expansion like placed under pressure or installed in limited space.

Contamination of the PPTC material with certain silicon based oils or some aggressive solvents can adversely impact the performance of the devices.PPTC SMD can be cleaned by standard methods.

· Requests that customers comply with our recommended solder pad layouts and recommended reflow profile. Improper board layouts or reflow profile could negatively impact solderability performance of our devices..